

FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	58059/N75
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)	Application Number	To be assigned
	Filing Date	July 24, 2006
	Applicant(s)	Jean-Louis Stehle
	Group Art Unit	To be assigned
	Examiner Name	To be assigned

**U.S. PATENT DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	DOCUMENT NUMBER Number - Kind Code <sup>2</sup> (If Known)	Publication Date MM-DD-YYYY	Name of Patentee
		5,474,865	12-12-1995	Vasudev
		6,280,886	08-28-2001	Yan
		2002/0018941 A1	02-14-2002	Matsumoto et al.
		6,492,067 B1	12-10-2002	Klebanoff et al.
		6,623,893 B1	09-23-2003	Levinson et al.

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	FOREIGN PATENT DOCUMENT Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T <sup>6</sup> ( <input checked="" type="checkbox"/> )
		WO 03/096121 A2	11-20-2003	Thony et al.	English abstract

**OTHER DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Maldonado, J.R., et al., Pellicles for X-Ray Lithography Masks, Etec Systems, Inc., SPIE Vol. 3331, pgs. 245-254 June 1998.
		International Search Report, dated January 3, 2006, Corresponding to PCT/FR2005/000168

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